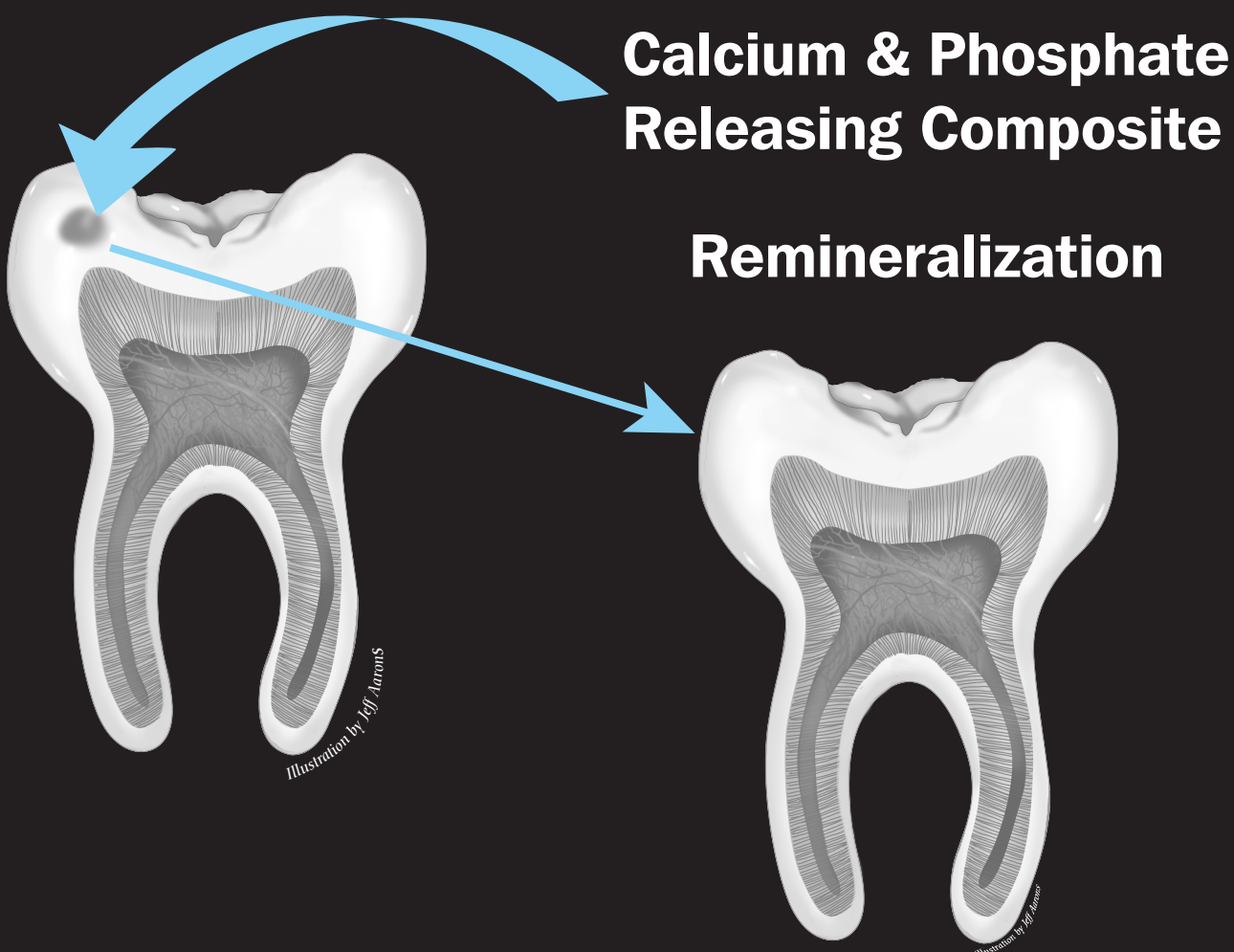


Journal of Research

of the

National Institute of Standards and Technology

May - June 2003, Vol. 108, No. 3 ISSN 1044-677X



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National Institute of Standards and Technology
Technology Administration, U.S. Department of Commerce

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¹At Boulder, CO 80303

²Some elements at Boulder, CO

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Volume 108

Number 3

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Cover: The cover illustration is an idealized schematic diagram depicting the remineralization of a small cavity in tooth enamel by the sustained release of calcium and phosphate ions from a polymeric composite sealant filled with amorphous calcium phosphate (see paper by Skrtic, Antonucci, and Eanes on page 167 of this issue). Cover art by Jeffrey Aarons.

The *Journal of Research of the National Institute of Standards and Technology*, the flagship periodic publication of the national metrology institute of the United States, features advances in metrology and related fields of physical science, engineering, applied mathematics, statistics, biotechnology, and information technology that reflect the scientific and technical programs of the Institute. The *Journal* publishes papers on instrumentation for making accurate measurements, mathematical models of physical phenomena, including computational models, critical data, calibration techniques, well-characterized reference materials, and quality assurance programs that report the results of current NIST work in these areas. Occasionally, a Special Issue of the *Journal* is devoted to papers on a single topic. Also appearing on occasion are review articles and reports on conferences and workshops sponsored in whole or in part by NIST.

ISSN 1044-677X

Coden: JRITEF

Library of Congress Catalog Card No.: 89-656121

United States Government Printing Office, Washington: 2003

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Available online
<http://www.nist.gov/jres>

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